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**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20596A**Generic Copy

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**Issue Date:** 9-Sep-2014**TITLE:** Qualification of CZ4 Fab (Czech Republic) as an additional wafer source for N-Channel and P-Channel JFET.**PROPOSED FIRST SHIP DATE:** 10-Dec-2014**AFFECTED CHANGE CATEGORY(S):** ON Semiconductor Fab Site**FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:**

Contact your local ON Semiconductor Sales Office or Farrah Omar &lt;farrah.omar@onsemi.com&gt;

**SAMPLES:** Contact your local ON Semiconductor Sales Office**ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or Laura Rivers &lt;laura.rivers@onsemi.com&gt;

**NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact &lt;quality@onsemi.com&gt;.

**DESCRIPTION AND PURPOSE:**

This is the Final Notification by ON Semiconductor notifying customers of its plan to qualify CZ4 Fab (Czech Republic) as an additional wafer source from current ISMF Fab (Malaysia) for N-Channel and P-Channel JFET.

The CZ4 Fab facility is an ON Semiconductor owned wafer fab that has been producing products for ON Semiconductor. Several existing technologies within ON Semiconductor's product families are currently sourced from CZ4 Fab. ON Semiconductor CZ4 Wafer Fab is an internal factory that is TS16949, ISO-9001 and ISO-14000 certified.

Qualification tests are designed to show that the reliability of the devices will continue to meet or exceed ON Semiconductor standards.

**FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #20596A****RELIABILITY DATA SUMMARY:****Package: SOT23****MMBFJ310LT1G**

<b>Test:</b>	<b>Conditions:</b>	<b>Interval:</b>	<b>Results</b>
HTRB	TA=150C,80% Rated Voltage	1008 hrs	0/84
HTGB	Ta = 150C, 100% Vgss	1008 hrs	0/84
HAST+PC	Ta=130C RH=85% bias=80% rated V or100V Max	96 hrs	0/84
UHASt+PC	Ta=130C RH=85%	96 hrs	0/84
TC+PC	Ta= -65 C to 150 C	1000 cyc	0/84

**MMBFJ175LT1G**

<b>Test:</b>	<b>Conditions:</b>	<b>Interval:</b>	<b>Results</b>
HTRB	TA=150C,80% Rated Voltage	1008 hrs	0/84
HTGB	Ta = 150C, 100% Vgss	1008 hrs	0/84
HAST+PC	Ta=130C RH=85% bias=80% rated V or100V Max	96 hrs	0/84
UHASt+PC	Ta=130C RH=85%	96 hrs	0/84
TC+PC	Ta= -65 C to 150 C	1000 cyc	0/84

**ELECTRICAL CHARACTERISTIC SUMMARY:**

There are no changes in electrical characteristics and product performance meets data sheet Specifications. Characterization data is available upon request.

**CHANGED PART IDENTIFICATION:**

Affected products from ON Semiconductor with date code 1450 representing WW50, 2014 and greater may be sourced from either the CZ4 Fab (Czech Republic) or the ISMF Fab (Malaysia).

**List of affected General Parts:**

SMMBFJ175LT1G  
SMMBFJ177LT1G